IGBT - Induction Cooking

This Insulated Gate Bipolar Transistor (IGBT) features a robust and cost effective Field Stop (FS) Trench construction, provides and superior performance in demanding switching applications, and offers low on-state voltage with minimal switching loss. The IGBT is well suited for resonant or soft switching applications.

Features

- Extremely Efficient Trench with Fieldstop Technology
- Low Switching Loss Reduces System Power Dissipation
- Optimized for Low Losses in IH Cooker Application
- This is a Pb-Free Device

Typical Applications

- Inductive Heating
- Consumer Appliances
- Soft Switching

ABSOLUTE MAXIMUM RATINGS

Rating	Symbol	Value	Unit
Collector-emitter voltage @ T _J = 25°C	V _{CES}	1200	V
Collector current @ Tc = 25°C @ Tc = 100°C	lc	40 20	А
Pulsed collector current, T_{pulse} limited by T_{Jmax} , 10 μs Pulse, V_{GE} = 15 V	I _{CM}	80	Α
Diode forward current @ Tc = 25°C @ Tc = 100°C	l _F	40 20	А
Diode pulsed current, T_{pulse} limited by T_{Jmax} , 10 μs Pulse, $V_{GE} = 0$ V	I _{FM}	80	А
Gate-emitter voltage Transient Gate-emitter voltage $(T_{pulse} = 5 \mu s, D < 0.10)$	V_{GE}	±20 ±25	V
Power Dissipation @ Tc = 25°C @ Tc = 100°C	P _D	341 170	W
Operating junction temperature range	T_J	-40 to +175	°C
Storage temperature range	T _{stg}	-55 to +175	°C
Lead temperature for soldering, 1/8" from case for 5 seconds	T _{SLD}	260	°C

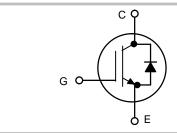
Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

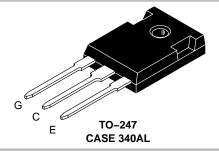


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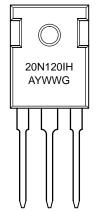
www.onsemi.com

20 A, 1200 V **V_{CEsat} = 2.20 V** $E_{off} = 0.48 \text{ mJ}$





MARKING DIAGRAM



= Assembly Location Α

= Year WW = Work Week = Pb-Free Package

ORDERING INFORMATION

Device	Package	Shipping
NGTB20N120IHWG	TO-247 (Pb-Free)	30 Units / Rail

THERMAL CHARACTERISTICS

Rating	Symbol	Value	Unit
Thermal resistance junction-to-case	$R_{ heta JC}$	0.44	°C/W
Thermal resistance junction-to-ambient	$R_{ heta JA}$	40	°C/W

ELECTRICAL CHARACTERISTICS (T_J = 25°C unless otherwise specified)

Parameter	Test Conditions	Symbol	Min	Тур	Max	Unit
STATIC CHARACTERISTIC						
Collector–emitter breakdown voltage, gate–emitter short–circuited	$V_{GE} = 0 \text{ V}, I_{C} = 500 \mu\text{A}$	V _{(BR)CES}	1200	_	_	V
Collector-emitter saturation voltage	V _{GE} = 15 V, I _C = 20 A V _{GE} = 15 V, I _C = 20 A, T _J = 175°C	V_{CEsat}	- -	2.20 2.30	2.65	V
Gate-emitter threshold voltage	$V_{GE} = V_{CE}, I_{C} = 250 \mu A$	V _{GE(th)}	4.5	5.5	6.5	V
Collector–emitter cut–off current, gate– emitter short–circuited	$V_{GE} = 0 \text{ V}, V_{CE} = 1200 \text{ V}$ $V_{GE} = 0 \text{ V}, V_{CE} = 1200 \text{ V}, T_{J=} 150^{\circ}\text{C}$	I _{CES}	-	_ _	0.1 2.8	mA
Gate leakage current, collector–emitter short–circuited	V _{GE} = 20 V, V _{CE} = 0 V	I _{GES}	_	_	100	nA
DYNAMIC CHARACTERISTIC		•				•
Input capacitance	V _{CE} = 20 V, V _{GE} = 0 V, f = 1 MHz	C _{ies}	-	3590	-	pF
Output capacitance		C _{oes}	-	90	-	
Reverse transfer capacitance		C _{res}	-	70	-	
Gate charge total		Q_g	-	150	-	nC
Gate to emitter charge	$V_{CE} = 600 \text{ V}, I_{C} = 20 \text{ A}, V_{GE} = 15 \text{ V}$	Q _{ge}	-	31	-	
Gate to collector charge		Q _{gc}	-	67	-	
SWITCHING CHARACTERISTIC, INDUCT	TIVE LOAD					
Turn-off delay time	$T_J = 25^{\circ}\text{C}$ $V_{CC} = 600 \text{ V, } I_C = 20 \text{ A}$ $R_q = 10 \Omega$	t _{d(off)}	-	170	-	ns
Fall time		t _f	-	155	-	
Turn-off switching loss	V _{GE} = 0 V/ 15V	E _{off}	-	0.48	-	mJ
Turn-off delay time	T _J = 150°C	t _{d(off)}	_	185	_	ns
Fall time	$V_{CC} = 600 \text{ V}, I_{C} = 20 \text{ A}$ $R_{\alpha} = 10 \Omega$	t _f	-	210	-	
Turn-off switching loss	$V_{GE} = 0 \text{ V} / 15 \text{V}$	E _{off}	1	0.92	1	mJ
DIODE CHARACTERISTIC			_			
Forward voltage	V _{GE} = 0 V, I _F = 20 A V _{GE} = 0 V, I _F = 20 A, T _J = 175°C	V _F	_ _	2.2 3.8	2.75	V
		L.				

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

TYPICAL CHARACTERISTICS

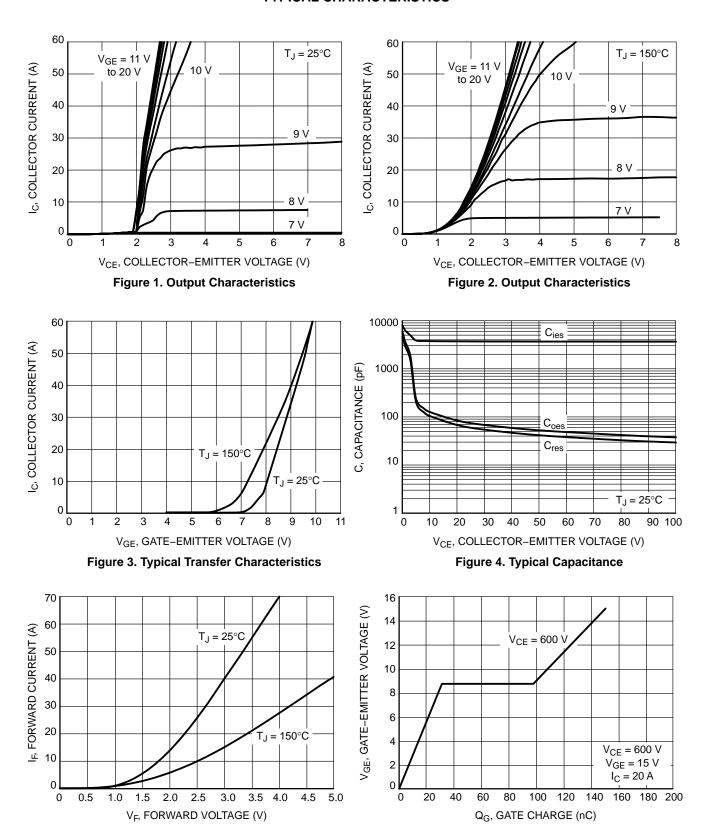


Figure 5. Diode Forward Characteristics

Figure 6. Typical Gate Charge

TYPICAL CHARACTERISTICS

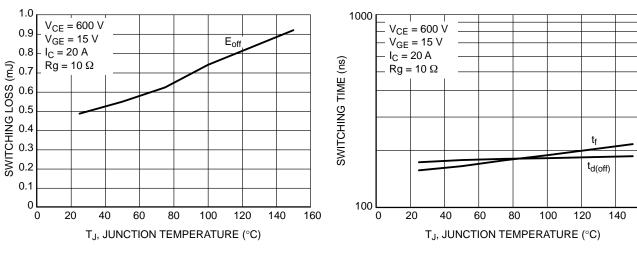


Figure 7. Switching Loss vs. Temperature

Figure 8. Switching Time vs. Temperature

160

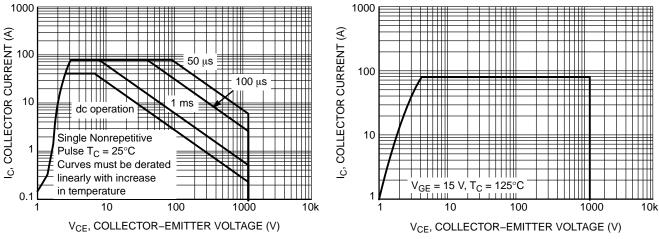


Figure 9. Safe Operating Area

Figure 10. Reverse Bias Safe Operating Area

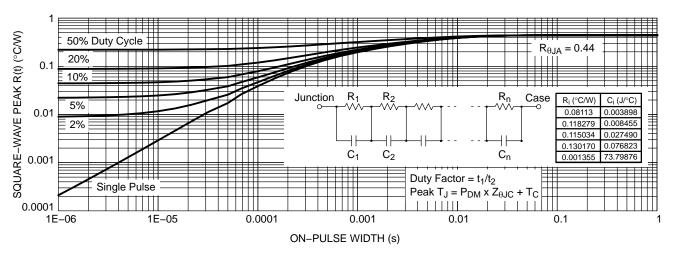


Figure 11. IGBT Transient Thermal Impedance

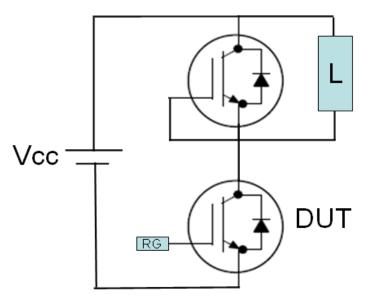


Figure 12. Test Circuit for Switching Characteristics

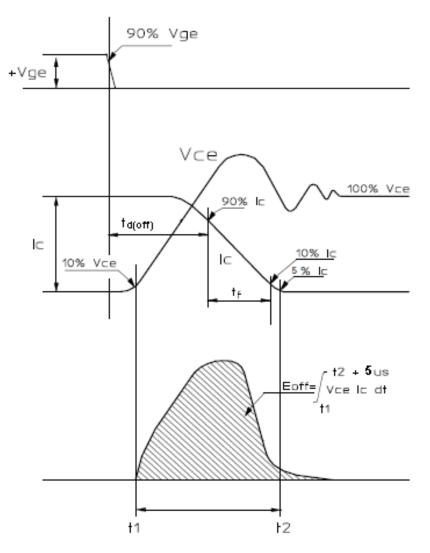
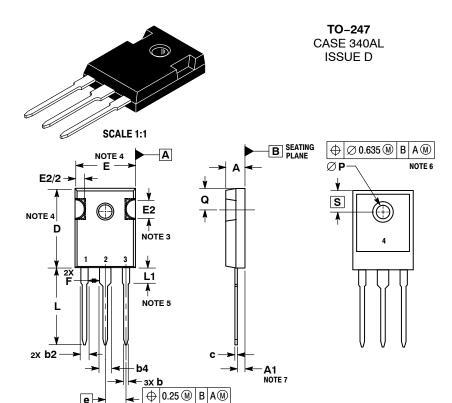


Figure 13. Definition of Turn Off Waveform

e -



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- NOTES:

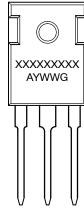
 1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1994.
 2. CONTROLLING DIMENSION: MILLIMETERS.
 3. SLOT REQUIRED, NOTCH MAY BE ROUNDED.

 - DIMENSIONS D AND E DO NOT INCLUDE MOLD FLASH.
 MOLD FLASH SHALL NOT EXCEED 0.13 PER SIDE. THESE DIMENSIONS ARE MEASURED AT THE OUTERMOST EXTREME OF THE PLASTIC BODY
- LEAD FINISH IS UNCONTROLLED IN THE REGION DEFINED BY
- ©P SHALL HAVE A MAXIMUM DRAFT ANGLE OF 1.5° TO THE TOP OF THE PART WITH A MAXIMUM DIAMETER OF 3.91.

 DIMENSION A1 TO BE MEASURED IN THE REGION DEFINED

	MILLIMETERS		
DIM	MIN	MAX	
Α	4.70	5.30	
A1	2.20	2.60	
b	1.07	1.33	
b2	1.65	2.35	
b4	2.60	3.40	
С	0.45	0.68	
D	20.80	21.34	
Е	15.50	16.25	
E2	4.32	5.49	
е	5.45 BSC		
F	2.655		
L	19.80	20.80	
L1	3.81	4.32	
P	3.55	3.65	
Q	5.40	6.20	
S	6.15 BSC		

GENERIC MARKING DIAGRAM*



XXXXX = Specific Device Code Α = Assembly Location

Υ = Year WW = Work Week = Pb-Free Package

*This information is generic. Please refer to device data sheet for actual part marking.

Pb-Free indicator, "G" or microdot " ■", may or may not be present.

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